

# Flexibility of the $MPS_4^-$ Chains of the $KMPS_4$ ( $M = Ni, Pd$ ) Compounds Studied by Molecular Orbital Calculations and Atomic Force Microscopy Measurements

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The flexibility of the  $MPS_4^-$  chains of  $KMPS_4$  ( $M = Ni, Pd$ ) was examined by performing contact mode atomic force microscopy (AFM) measurements for the (001) surface of  $KNiPS_4$  and also by performing extended Hückel tight binding calculations for the  $[M(PS_4)_2]^{4-}$  entities of  $KMPS_4$ . The observed AFM images were analyzed by calculating the total electron density plots for an isolated  $[NiPS_4]^-$  slab of the (001) surface. Our calculations show that the  $PS_4^{3-}$  ions are more strongly bound to the  $Pd^{2+}$  ions in  $KPdPS_4$  than to the  $Ni^{2+}$  ions in  $KNiPS_4$ , and that the bonding between the  $PS_4^{3-}$  anions and  $M^{2+}$  ( $M = Ni, Pd$ ) cations is flexible with respect to the rotational motions of the  $PS_4^{3-}$  anions. The AFM images recorded for the (001) surface of  $KNiPS_4$  indicate that the  $PS_4^{3-}$  anions on the surface undergo a rotational relaxation when the scanning tip passes by. © 1999

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## 1. INTRODUCTION

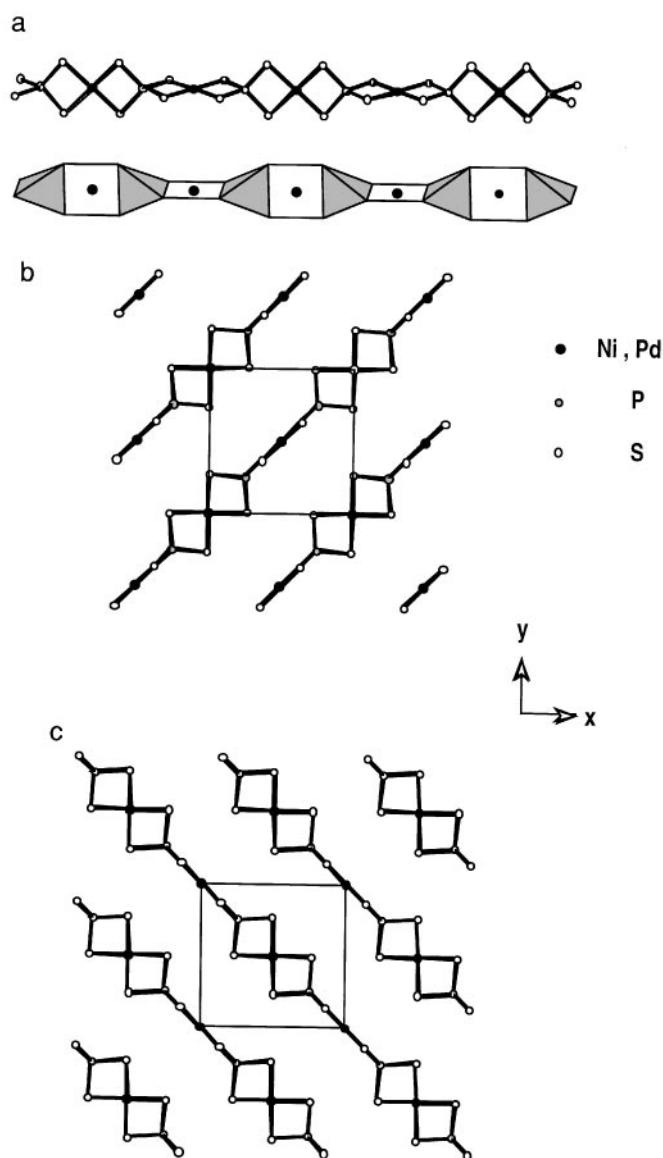
The structures of the compounds  $KMPS_4$  ( $M = Ni, Pd$ ) (1, 2) contain the  $MPS_4^-$  chains made up of  $PS_4^{3-}$  tetrahedra and  $M^{2+}$  ( $d^8$ ) cations (Fig. 1a). Every  $M^{2+}$  ion is located at the center of a square planar unit  $MS_4$  sharing edges with two adjacent  $PS_4^{3-}$  tetrahedra, so that adjacent  $MS_4$  units are perpendicular to each other. These chains form layers of  $MPS_4^-$  chains parallel to the  $ab$ -plane as shown in Figs. 1b and 1c. The chain direction of Fig. 1b is perpendicular to that of Fig. 1c. These two kinds of layers alternate along the  $c$ -axis direction, and the  $K^+$  ions reside between the layers at the sites made up of eight S atoms.

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When the  $KMPS_4$  compounds are dissolved in a polar organic solvent such as dimethylformamide (DMF), the  $MPS_4^-$  chains become flexible polymer chains (3, 4). In the DMF solution of  $KNiPS_4$ , fragmentation and rearrangement take place to form trimer units  $[(NiPS_4)_3]^{3-}$ . However, in the DMF solution of  $KPdPS_4$ , this phenomenon does not occur and the  $PdPS_4^-$  chains are maintained at room temperature (3, 4). As demonstrated by force valence field calculations (4), these observations imply that the  $PS_4^{3-}$  anions are more strongly bound to the  $Pd^{2+}$  cations than to the  $Ni^{2+}$  cations. Moreover, the chemical and physical properties of the  $MSP_4^-$  chains in solution indicate that the bending and rotational motions of the  $PS_4^{3-}$  anions in a  $MPS_4^-$  chain (Figs. 2a and 2b, respectively) do not require much energy.

The above implications can be easily verified by performing molecular orbital calculations for the  $[M(PS_4)_2]^{4-}$  unit that is formed between the  $M^{2+}$  and two  $PS_4^{3-}$  ions. However, it is desirable to find another piece of experimental evidence supporting the flexibility of bonding between the  $M^{2+}$  and the two  $PS_4^{3-}$  ions. Scanning tunneling and atomic force microscopy (AFM) have shown (5, 6) that during imaging, nonequivalent atoms of surface undergo different degrees of local structure relaxation under the repulsive forces the tip exerts to the surface. The tip-force induced surface relaxation can modify the local electronic structure of a surface (7) and can even bring about a reversible rearrangement of weak metal–metal bonds (8). As shown in Fig. 1, the (001) surface of  $KMPS_4$  consists of parallel  $MPS_4^-$  chains in which the square planar  $MS_4$  units are either perpendicular or parallel to the surface. Thus, when the (001) surface of  $KMPS_4$  is examined by AFM, the scanning tip might induce the rotation of the  $PS_4^{3-}$  anions



**FIG. 1.** Structure building blocks of  $\text{KMPS}_4$ : (a) Two perspective views of a  $\text{MPS}_4^-$  chain. In the lower representation, each  $\text{PS}_4^{3-}$  anion is represented by a shaded tetrahedron. (b, c) Projection views of two adjacent layers of  $\text{MPS}_4^-$  chains, where the square boxes represent a unit cell.

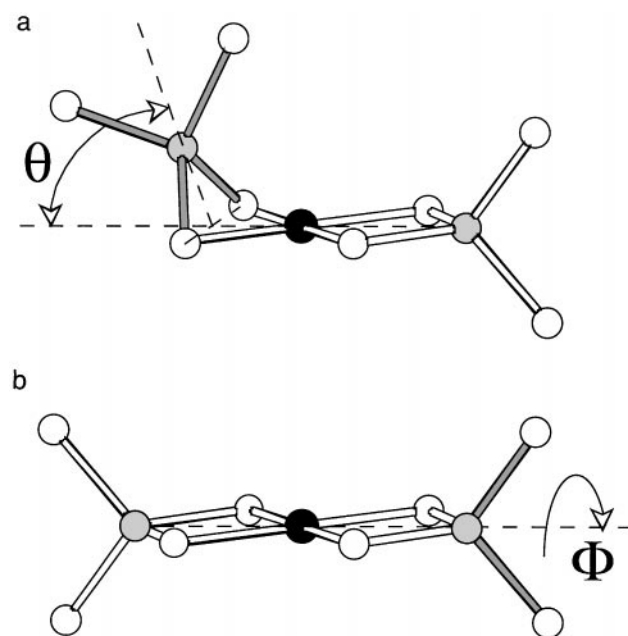
on the surface if the rotational motion of the  $\text{PS}_4^{3-}$  anions (Fig. 2b) does not require much energy as suggested by the dissolution studies (3,4). Thus, AFM images of  $\text{KMPS}_4$  may differ substantially than those expected for the ideal (001) surface taken from the bulk crystal structure. In the present work, we examine the flexibility of the  $\text{MPS}_4^-$  chains in the solid state by studying the (001) surface of  $\text{KNiPS}_4$  with AFM and also by performing molecular orbital calculations for the  $[\text{M}(\text{PS}_4)_2]^{4-}$  unit ( $M = \text{Ni, Pd}$ ) using the extended Hückel tight-binding (EHTB) method (9, 10).

## 2. BINDING ENERGIES AND ROTATIONAL POTENTIALS

The  $[\text{M}(\text{PS}_4)_2]^{4-}$  ( $M = \text{Ni, Pd}$ ) unit is made up of the  $M^{2+}$  ( $d^8$ ) cation and two  $\text{PS}_4^{3-}$  anions. Thus, the binding energy  $\Delta E$  of the  $[\text{M}(\text{PS}_4)_2]^{4-}$  unit can be estimated from the energy of the  $[\text{M}(\text{PS}_4)_2]^{4-}$  unit by subtracting the energy of the  $M^{2+}$  cation and two  $\text{PS}_4^{3-}$  anions. Calculations of the  $\Delta E$  values show that the  $M^{2+}$  and  $\text{PS}_4^{3-}$  ions are more strongly bound in  $[\text{Pd}(\text{PS}_4)_2]^{4-}$  than in  $[\text{Ni}(\text{PS}_4)_2]^{4-}$  by 63 kJ/mol. This is consistent with the experimental observation that a fragmentation–rearrangement process takes place in the DMF solution of  $\text{KNiPS}_4$ , but not in the DMF solution of  $\text{KPdPS}_4$  (3, 4). Figure 3 shows the rotational potential energy curves calculated for  $[\text{M}(\text{PS}_4)_2]^{4-}$  as a function of the rotational angle  $\phi$  defined in Fig. 2b. The potential is soft for both  $[\text{Pd}(\text{PS}_4)_2]^{4-}$  and  $[\text{Ni}(\text{PS}_4)_2]^{4-}$ . For example, at  $\phi = 40^\circ$ , the potential energy increases are only 20 and 26 kJ/mol for  $[\text{Ni}(\text{PS}_4)_2]^{4-}$  and  $[\text{Pd}(\text{PS}_4)_2]^{4-}$ , respectively. Thus, the  $\text{PS}_4^{3-}$  anions of the  $\text{M}(\text{PS}_4)^-$  chains can easily rotate away from the square planar  $\text{MS}_4$  arrangements.

## 3. CHARACTERIZATION OF THE (001) SURFACE BY AFM

Contact-mode AFM measurements were made on freshly cleaved surfaces of the mounted crystal samples of  $\text{KNiPS}_4$  at ambient conditions using a commercial scanning probe microscope Nanoscope III (Digital Instruments, Inc.) and



**FIG. 2.** (a) Bending and (b) rotational motions of one  $\text{PS}_4^{3-}$  anion in the  $[\text{M}(\text{PS}_4)_2]^{4-}$  unit.

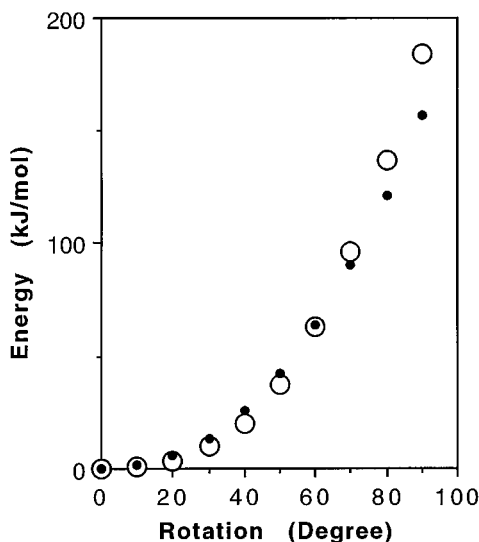


FIG. 3. Rotational potential energy curves calculated for the  $[M(PS_4)_2]^{4-}$  unit as a function of the rotational angle  $\phi$ . The large empty and small filled circles represent  $M = Ni$  and  $M = Pd$ , respectively.

commercial cantilevers with  $Si_3N_4$  tips. Atomic-scale images were recorded in the height imaging mode. To observe image contrast, it was necessary to use a weak cantilever with long and thin arms as well as low set-point forces (about 20 nN). Use of higher forces resulted in a poor image quality or even the loss of any image contrast. Images corresponding to the surface slab of  $K^+$  cations were not observed, and this is due most probably to the mechanical instability of such a layer.

AFM images of a surface are well described by the total electron density plot  $\rho(r_0)$  calculated for the surface (5). To simulate the  $\rho(r_0)$  plot for the (001) surface of  $KNiPS_4$ , we use a single layer of  $NiPS_4^-$  chains taken from the bulk crystal structure of  $KNiPS_4$ . The  $\rho(r_0)$  plots were calculated using the EHTB method (9–11) with the tip placed at 0.5 Å above the highest-lying atoms of the sample surface (i.e.,  $r_0 = 0.5$  Å). The essential features of these plots do not depend on  $r_0$ .

Figure 4a shows the  $\rho(r_0)$  plot calculated for a single layer of  $NiPS_4^-$  chains taken from the bulk crystal structure of  $KNiPS_4$ . In this layer, the arrangements of the  $PS_4^{3-}$  anions were kept as in the bulk crystal structure of  $KNiPS_4$  (see Fig. 1b). The surface represented by this layer is an unrelaxed one and will be referred to as the  $(0^\circ, 0^\circ)$ -structure (see below). As expected from the topography of this unrelaxed surface, the high electron density (HED) spots of the  $\rho(r_0)$  plot correspond to the highest-lying S atom of each  $PS_4^{3-}$  anion. Thus, if no surface relaxation takes place during AFM measurements, there should be two equally bright spots per unit cell in the AFM images recorded for the (001) surface of  $KNiPS_4$ . However, the observed AFM images differ from this picture, as will be discussed below.

Figure 5a shows a representative AFM image recorded for the (001) surface of  $KNiPS_4$ . To emphasize the periodic features of this image, a zoomed part of this image was filtered using the fast Fourier transform procedure as presented in Fig. 5b. This image shows one bright and three less bright spots per unit cell. The distance between the brightest spots are 9.1 Å, which compare well with the corresponding value (i.e., 8.2538 Å) determined from the crystal structure within the typical experimental error of 10% in AFM measurements. The distances from the brightest to the less bright spots are about 4.1 and 3.6 Å from the image, which correspond to 3.7 and 3.2 Å, respectively, when scaled down by the factor of 8.3/9.1. The distance of 3.7 Å is comparable in length to the longest S...S distance (3.548 Å) found within a  $PS_4^{3-}$  anion. Likewise, the distance of 3.2 Å is comparable in length to the shortest S...S distance (3.177 Å) between two adjacent  $PS_4^{3-}$  anions (i.e., one S...S side of the  $NiS_4$  square).

To explain why the observed AFM images of  $KNiPS_4$  exhibit more than two bright spots per unit cell, we suppose that the  $PS_4^{3-}$  anions undergo a rotational motion around the chain axis in order to reduce the tip-sample repulsive interaction associated with the higher-lying sulfur atoms. When a  $PS_4^{3-}$  anion undergoes a rotation from the unrelaxed structure, the highest-lying S atom is lowered in height. At the same time, the rotation raises the height of one of the two S atoms lying in the  $NiS_4$  plane parallel to the

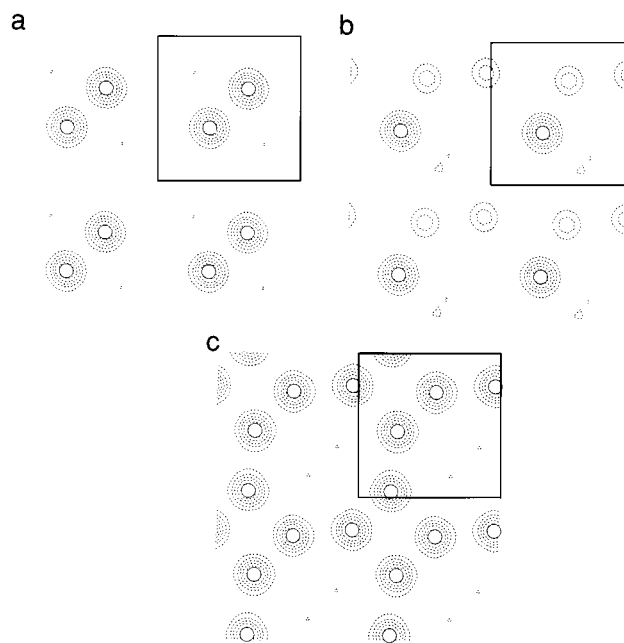
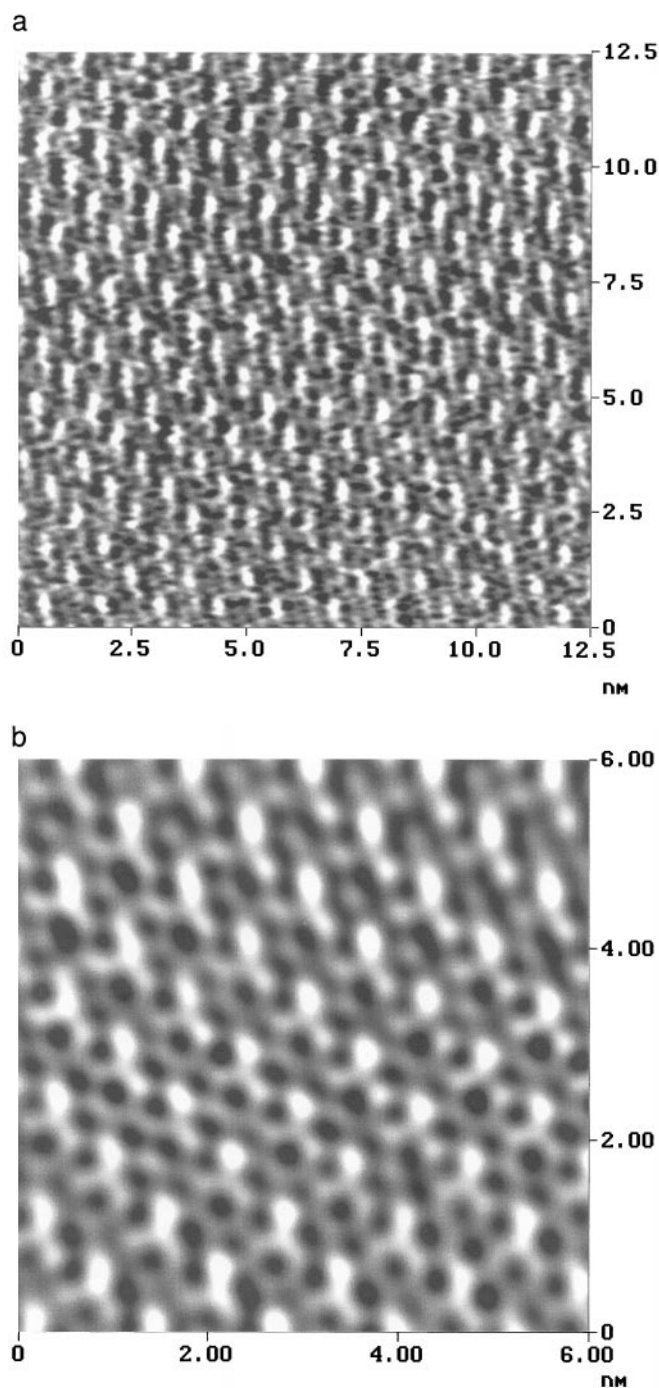


FIG. 4.  $\rho(r_0)$  plots calculated for the (001) surface of  $KNiPS_4$ . The plots in (a), (b), and (c) refer to the  $(0^\circ, 0^\circ)$ -,  $(0^\circ, 45^\circ)$ -, and  $(45^\circ, 45^\circ)$ -structures, respectively (see the text). The values of the contour lines are 0.04, 0.07, 0.11, 0.15, and 0.19 electrons/au<sup>3</sup>, and the circles represent the highest-lying S atoms.



**FIG. 5.** Representative AFM height images recorded for the (001) surface of KNiPS<sub>4</sub> with the scan rate of 20.35 Hz. (a) Unfiltered image. (b) Filtered image. The contrast variation covers from 0.0 to 1.0 nm.

(001) surface (see Fig. 1a). When a PS<sub>4</sub><sup>3-</sup> anion is rotated by 45°, its highest-lying two S atoms have the same height. For simplicity, we will consider two extreme cases of the PS<sub>4</sub><sup>3-</sup> anion rotation. In one case every second PS<sub>4</sub><sup>3-</sup> anion of each NiPS<sub>4</sub>- chain is rotated by 45°, and the resulting layer of NiPS<sub>4</sub>- chains will be referred to as the (0°, 45°)-structure. In

the other case, every PS<sub>4</sub><sup>3-</sup> anion of each NiPS<sub>4</sub>- chain is rotated by 45°, and the resulting layer of NiPS<sub>4</sub>- chains will be referred to as the (45°, 45°)-structure, in which the Ni atoms remain in square-planar environments. Figures 4b and 4c show the  $\rho(r_0)$  plots calculated for the (0°, 45°)- and the (45°, 45°)-structures, respectively. These plots show that depending on the extent of the rotation, each PS<sub>4</sub><sup>3-</sup> anion can contribute two HED spots.

When the angle of rotation is less than 45°, two complications arise. First, the two highest-lying S atoms of PS<sub>4</sub><sup>3-</sup> are unequal in heights so that their HED spots will have unequal densities. Second, the lateral positions of these unequal HED spots depend on the sense of the rotational direction (e.g., +30° vs -30°). AFM measurements involve a large tip-sample contact area (5), and the sense and the magnitude of rotation may not be the same for all the PS<sub>4</sub><sup>3-</sup> anions in the tip-sample contact area. Therefore, the observed AFM images should represent an average of all these complex contributions. Our assumption that the PS<sub>4</sub><sup>3-</sup> ions on the (001) surface undergo a rotational relaxation provides a natural explanation for why the observed AFM image shows more than two bright spots per unit cell.

#### 4. CONCLUDING REMARKS

Our calculations show that the PS<sub>4</sub><sup>3-</sup> ions are more strongly bound to the Pd<sup>2+</sup> ions in KPdPS<sub>4</sub> than to the Ni<sup>2+</sup> ions in KNiPS<sub>4</sub>, in support of the observation of the dissolution studies (3, 4). Furthermore, our calculations show soft potential curves for the rotation of the PS<sub>4</sub><sup>3-</sup> anions around the MPS<sub>4</sub>- chain axis. Thus, during AFM imaging, the PS<sub>4</sub><sup>3-</sup> anions are expected to undergo a rotational relaxation to reduce the tip-sample repulsive interaction associated with the higher-lying sulfur atoms. In agreement with this expectation, the AFM images recorded for the (001) surface of KNiPS<sub>4</sub> exhibit a brightness pattern different than the one expected for the unreconstructed (001) surface. This provides a strong support for the observation of the dissolution studies (3, 4) that the MPS<sub>4</sub>- chains of the compounds KMPS<sub>4</sub> (M = Ni, Pd) are flexible.

#### ACKNOWLEDGMENTS

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